

Supporting Information

Light Scattering Behavior by Nanostructured Antireflection

Coatings

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To investigate the crystalline characteristics of the ZnO seed layers spin-coated at 500 rpm, 1500 rpm, and 2000 rpm, the X-ray diffraction (XRD) was characterized. The XRD results are shown in Fig. S1. Since the thickness of ZnO seed layers is smaller than 5 nm, the intensity of XRD is low. The (002) peak for the 500-rpm ZnO seed layer exhibits a substantially great intensity, further confirming that the degree of crystal orientation along *c*-axis is the highest in 500-rpm seed layer. Consequently, NRAs grown on 500-rpm seed layers grow perpendicularly, as shown in Fig. 1(a). Compared with the 2000-rpm seed layer with no obvious XRD peak, 1500-rpm seed layer presents the weak (101) peak of ZnO, indicating that the 1500-rpm seed layer has preferential orientation along the [101] direction and low tendency toward random orientation and thus provides relatively preferential nanorod growth direction. Therefore, the tilt angle and the number of tilted NRAs grown on 1500-rpm seed layer

are smaller than on 2000-rpm seed layer.

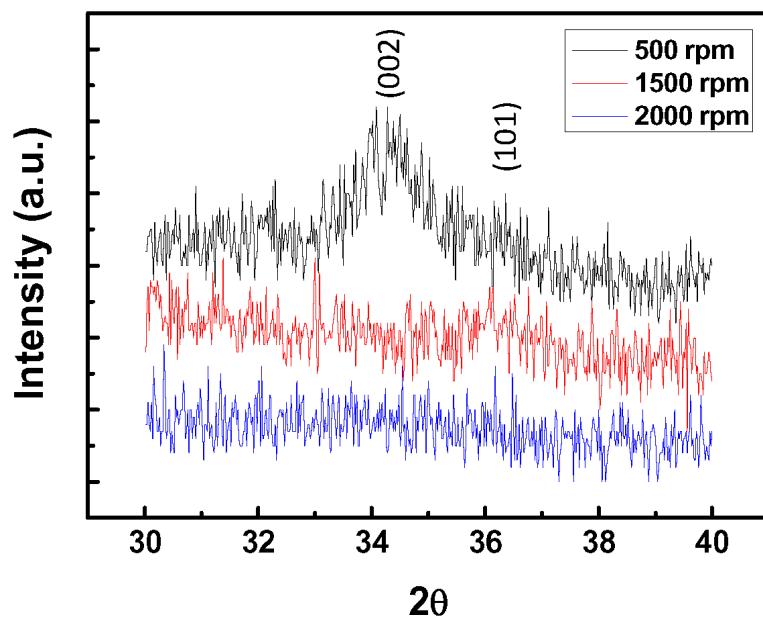


Figure S1